

Notice of References Cited

Application/Control No.

10/565,863

Applicant(s)/Patent Under
Reexamination
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Examiner

JOHN Wahnkyo LEE

Art Unit

2624

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*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
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	B	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.